



Product/Process Change Notice - PCN 19_0142 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: LTM2884 Notification of Change, New Transformer

Publication Date: 12-Aug-2019

Effectivity Date: 14-Nov-2019 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change:

The internal power transformer was re-designed for production at two alternate suppliers. This also necessitated updating to a newer LTC flyback power die that uses fewer discrete components. Internal substrate changes were made to accept the transformer and component changes. The USB die and protection components are unchanged.

The change has been fully characterized over the full operating temperature range. A full qualification has been completed. Re-certification to UL1577 is in process.

Reason For Change:

Analog Devices Corporation has made a change to the LTM2884 uModule due to a supplier issue.

Impact of the change (positive or negative) on fit, form, function & reliability:

One parametric specification must be relaxed, Regulated VCC2 Output Voltage, Loaded increases from 4.75V – 5.25V to 4.5V – 5.5V. This new 10% range still satisfies the USB specification. Lastly, ICC quiescent current improves and tightens from a typical 50mA down to 9mA, and max reduces from 100mA to 35mA. No other functional or parametric specifications are affected.

Product Identification *(this section will describe how to identify the changed material)*

The product built using the new transformer and die will be available with a datecode of approximately 1948.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Revised Datasheet Specification

ADI_PCN_19_0142_Rev_-_LTM2884_datasheet_markup.pdf

Attachment 2: Type: Qualification Results Summary

ADI_PCN_19_0142_Rev_-_LTCM2884_New_Substrate_Transformer_Die_RelReport.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:
PCN_Americas@analog.com

Europe:
PCN_Europe@analog.com

Japan:
PCN_Japan@analog.com

Rest of Asia:
PCN_ROA@analog.com

Appendix A - Affected ADI Models

Added Parts On This Revision - Product Family / Model Number (6)

LTM2884 / DC1789A	LTM2884 / LB068A-A	LTM2884 / LTM2884CY#PBF	LTM2884 / LTM2884HY#PBF	LTM2884 / LTM2884IY#PBF
LTM2884 / LTP2884				

Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	12-Aug-2019	14-Nov-2019	Initial Release

Analog Devices, Inc.

DocId:6762 Parent DocId:None Layout Rev:7

RELIABILITY DATA
 LTM2884 New Substrate, Transformer, and Die Changes
 7/23/2019

• BIASED HIGHLY ACCELERATED STRESS TEST AT +130°C / 85%RH *					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	Equivalent K DEVICE HOURS AT +85°C**	NUMBER OF FAILURES
BGA 1515	100	1804	1812	192	0
Total	100			192	0
• UNBIASED HIGHLY ACCELERATED STRESS TEST AT +130°C / 85%RH *					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	Equivalent K DEVICE HOURS AT +85°C**	NUMBER OF FAILURES
BGA 1515	308	1804	1812	591.36	0
Total	308			591.36	0
• TEMPERATURE CYCLE TEST AT -55°C to +125°C *					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
BGA 1515	308	1804	1812	308	0
Total	308			308	0
• THERMAL SHOCK TEST AT -55°C to +125°C *					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
BGA 1515	308	1804	1812	308	0
Total	308			308	0
• HIGH TEMPERATURE STORAGE LIFE TEST AT +150°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
BGA 1515	200	1804	1812	200	0
Total	200			200	0
• Electrical Test and CSAM post JEDEC MSL 3+ Preconditioning (216h at 30°C/60% R.H. plus 3x IR at 245°C)					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
BGA 1515	96	1804	1812		0
Total	96				0

* Test is preceded by JEDEC Preconditioning: 192h 30°C/60% R.H. plus 3x IR at 245°C.

** Assumes 20X acceleration from +85°C to +130°C